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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/605,082	09/08/2003	MIN-LUNG HUANG	10228-US-PA	2081	
31561	7590 04/26/2004		EXAM	EXAMINER	
JIANQ CHYUN INTELLECTUAL PROPERTY OFFICE			TSAI, H JEY		
7 FLOOR-1,	NO. 100 T ROAD, SECTION 2		ART UNIT	PAPER NUMBER	
	00		2812		
TAIWAN			DATE MAILED: 04/26/2004	4	

Please find below and/or attached an Office communication concerning this application or proceeding.

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	Application No.	Applicant(s)	-, -
	10/605,082	HUANG ET AL.	
Office Action Summary	Examiner	Art Unit	
	H.Jey Tsai	2812	
The MAILING DATE of this communicatio Period for Reply	n appears on the cover sheet	with the correspondence address	
A SHORTENED STATUTORY PERIOD FOR RETHE MAILING DATE OF THIS COMMUNICATION of time may be available under the provisions of 37 Cafter SIX (6) MONTHS from the mailing date of this communication of the period for reply specified above is less than thirty (30) days of the If NO period for reply is specified above, the maximum statutory Failure to reply within the set or extended period for reply will, by Any reply received by the Office later than three months after the earned patent term adjustment. See 37 CFR 1.704(b).	ON. ERR 1.136(a). In no event, however, may on. , a reply within the statutory minimum of t period will apply and will expire SIX (6) M statute, cause the application to become	a reply be timely filed hirty (30) days will be considered timely. ONTHS from the mailing date of this communic ABANDONED (35 U.S.C. § 133).	cation.
Status			
1)☐ Responsive to communication(s) filed on 2a)☐ This action is FINAL . 2b)☒ 3)☐ Since this application is in condition for all closed in accordance with the practice unit	This action is non-final.		ts is
Disposition of Claims			
4) ☐ Claim(s) 9-16 is/are pending in the application Papers 9) ☐ The specification is objected to by the Example The specification is objected to a policy and policy are not request that any objection is not replacement drawing sheet(s) including the country is/are pending in the application with the application is solved. 5) ☐ Claim(s) is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and application Papers 9) ☐ The specification is objected to by the Example The applicant may not request that any objection is Replacement drawing sheet(s) including the country is objected to by the example The oath or declaration is objected to by the example The oath or declaration is objected to by the example Theorem Including the country is objected to by the example Theorem Including the country is objected to by the example Theorem Including the country is objected to by the example Theorem Including the country is objected to by the example Theorem Including the country is objected to by the example Theorem Including the country is objected to by the example Theorem Including the country is objected to by the example Theorem Including the country is objected to by the example Theorem Including the country is objected to be the example Theorem Including the country including the country is objected to be the example Theorem Including the country includin	and/or election requirement. aminer. 33 is/are: a) accepted or b to the drawing(s) be held in abey correction is required if the drawing	vance. See 37 CFR 1.85(a). ng(s) is objected to. See 37 CFR 1.13	
	TO Examinor. Note the attack		_ .
Priority under 35 U.S.C. § 119 12) Acknowledgment is made of a claim for for a) All b) Some * c) None of: 1. Certified copies of the priority docu 2. Certified copies of the priority docu 3. Copies of the certified copies of the application from the International E * See the attached detailed Office action for	ments have been received. ments have been received in e priority documents have be Bureau (PCT Rule 17.2(a)).	Application No en received in this National Stage	;
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-94) 3) Information Disclosure Statement(s) (PTO-1449 or PTO/94) Paper No(s)/Mail Date S. Patent and Trademark Office	Paper N	w Summary (PTO-413) lo(s)/Mail Date of Informal Patent Application (PTO-152)	

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Election/Restriction

Applicant's election without traverse of claims 9-16 in Paper filed on Feb. 17, 2004 is acknowledged.

Claim Rejections - 35 USC § 102

The following is a quotation of the appropriate paragraphs of 35 U.S.C. § 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless –

(e) the invention was described in (1) an application for patent, published under section 122(b), by another filed in the United States before the invention by the applicant for patent or (2) a patent granted on an application for patent by another filed in the United States before the invention by the applicant for patent, except that an international application filed under the treaty defined in section 351(a) shall have the effects for purposes of this subsection of an application filed in the United States only if the international application designated the United States and was published under Article 21(2) of such treaty in the English language.

Claims 9-16 are rejected under 35 U.S.C. § 102(e) as being anticipated by Kwon 2004/0012081 (Applicants may submit an English translation for consideration of the foreign priority over this reference).

Kwon discloses a chip structure, which includes:

a substrate 502/503 having an upper surface, fig. 7,

a die 501 (called active device) having an active surface and a back surface, wherein the active surface is implemented with a plurality of bonding pads, figs. 6a, 7-8, and para. 44-52,

an under-bump-metallurgy layer of composite metals (not shown in the figure) disposed over the bonding pads 501a, see para. 51 and fig. 8,

a plurality of solder blocks 610 respectively disposed above the under-bump-metallurgy layer, fig. 8 and para. 51,

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a passive component 102b/102c/104b/104c having a plurality of terminal electrodes, which is coupled to the UBM layer through the solder blocks 610, fig. 8,

a patterned dielectric layer 501b has a plurality of openings that expose the bonding pads 501a and the UBM layer is disposed above the patterned dielectric layer 501b, see para. 51 and fig. 8,

a re-distribution layer 501c is connected to the bonding pads 501a, para. 50 and fig. 8, a packaging plastic (called resin) 540 enclosing the die 501, the passive component 102b/102c or 104b/104c, and the conductive wire 504c, 504d, para. 046.

Claims 9-11 are rejected under 35 U.S.C. § 102(e) as being anticipated by Lin 2004/00029404 (Applicants may submit an English translation for consideration of the foreign priority over this reference).

Lin '404 discloses a chip structure, which includes:

a die 10 having an active surface and a back surface, wherein the active surface is implemented with a plurality of bonding pads 16, figs. 10-11, 2-5 and para. 137-140,

an under-bump-metallurgy layer 50 of metal disposed over the bonding pads 16, see para.

137,

a plurality of solder blocks 52 or 56 respectively disposed above the under-bump-metallurgy layer 50,

a passive component 54/53 of capacitor or inductor having a plurality of terminal electrodes, which are respectively coupled to the UBM layer 50 through the solder blocks 52 or 56,

a patterned dielectric layer 18 has a plurality of openings that expose the bonding pads 16 and the UBM layer 50 is disposed above the patterned dielectric layer 18, fig. 10 or fig. 11,

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a re-distribution layer 13 is connected to the bonding pads 16, para. 59.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 9-10, 12-13 and 15-16 are rejected under 35 U.S.C. 103(a) as being unpatentable over Kunimatsu et al. 5,767,564 in view of Ratificar et al. 2003/0121958 and Nguyen et al. 6,238,949.

The reference(s) teach the features:

Kunimatsu et al. substantially discloses a chip structure and a chip package structure, which includes:

a substrate 1 (called package) having an upper surface, fig. 1+ and col. 3, lines 34+, a die 2 (called semiconductor element) having an active surface and a back surface, wherein the back surface of the die 2 is in contact with the upper surface of the substrate 1 (called package) and the active surface is implemented with a plurality of bonding pads, see fig. 2-3, and col. 4, lines 13+,

a solder block 3A disposed on the die 2, figs. 2-3 and col. 4, lines 32+,

a passive component 3 (a capacitor) with a plurality of terminal electrodes 5, 7, 8 wherein the terminal electrodes are coupled to the solder block 3A, col. 4, lines 38+,

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a plurality of conductive wires electrically connecting the die 2 and the substrate 1.

Ratificar et al. teaches at figs. 1a-1e and para 16-26 and 38, a pattern dielectric layer 120 to form a via opening exposing the bonding pad 110, UBM layer 130 including gold formed over dielectric layer 120 and solder block 150.

Nguyen et al. teaches at col. 1, lines 15-22, col. 3, lines 34-38 using a plastic as an encapsulant for a chip package.

The difference between the reference(s) and the claims are as follows: Kunimatsu et al. teaches mounting a passive component of capacitor to a chip through a solder block but does not teach that a UBM and a bond pad are commonly formed under solder block and using plastic to encapsulate the die. However, Ratificar et al. teaches at para. 16-26 and 38 and fig. 1d-1d, a UBM layer 130 and a bonding pad 110 formed under the solder block 150. And, Nguyen et al. teaches at col. 1, lines 15-22, col. 3, lines 34-38 using a plastic as encapsulant to form a packaged integrated circuit.

It would have been obvious to one having ordinary skill in the art at the time the invention was made to have modified Kunimatsu et al.'s process with a UBM, a bonding pad as suggested by Ratificar et al. and using a plastic package as suggested by Nguyen et al. because UBM can promote the adhesion of the solder block to the bonding pad and bonding pad provides a larger surface for making connection between the interconnection layer in the die to solder block, and plastic package is less expensive than other type of chip package.

Claims 11 and 14 are rejected under 35 U.S.C 103 as being unpatentable over Kunimatsu et al. in view of Ratificar et al. and Nguyen et al. as applied to claims 9-10, 12-13 and 15-16 above, and further in view of Lin 6,303,423.

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The difference between the references applied above and the instant claim(s) is: Primary reference Kunimatsu et al. in view of Ratificar et al. and Nguyen et al. does not teach a redistribution layer is connected to the bond pad. However, Lin '423 teach at col. 7, lines 37-53 and figure 4 and 11 that a network of electrical connections formed from conductive line 13 is connected to bonding pad 16.

It would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the above references' teachings with a re-distribution layer as taught by Lin '423 because passive component formed over the die can be re-distribute to the circuit formed in the die.

Any inquiry of a general nature or clerical matters or relating to the status of this application or proceeding should be directed to the Group customer service whose telephone number is 571-272-1626 and Fax number (703) 872-9306.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to H. Jey Tsai whose telephone number is (571) 272-1684. The examiner can normally be reached on from 7:00 Am to 4:00 Pm., Monday thru Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, John Niebling can be reached on (571) 272-1679. The fax phone number for this Group is (703) 872-9306.

hit

4/20/04

H. Jey Tsai

Primary Examiner
Patent Examining Group 2800